

Notice of References Cited

Application/Control No.

10/655,931

Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

3676

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0196403	10-2004	Lee	348/373
	B	US-2004/0082202	04-2004	Obermeyer, John R.	439/006
	C	US-2004/0139579	07-2004	Su, Ding-Hone	016/351
	D	US-6,804,861	10-2004	Hsu, Hsiang-Ti	16/366
	E	US-6,742,756	06-2004	Fimeri et al.	248/479
	F	US-6,742,221	06-2004	Lu et al.	16/367
	G	US-6,694,570	02-2004	Chen, Wu-Yung	16/367
	H	US-6,694,569	02-2004	Chien et al.	16/367
	I	US-6,256,837	07-2001	Lan et al.	16/334
	J	US-5,335,142	08-1994	Anderson, William J.	361/681
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11257343 A	09-1999	Japan	HIGANO et al.	F16C 11/10
	O	JP 2004053927 A	02-2004	Japan	TANIMOTO et al.	G09F 09/00
	P	JP 2003120652 A	04-2003	Japan	SATO, KATSUTOSHI	F16C 11/04
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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